9. A surface acoustic wave device comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within the range such that the power flow angle PFA of a Rayleigh wave is within about $\pm$ 2.5°; and

the Euler angles of said quartz substrate are within the range such that the electromechanical coupling coefficient for a spurious wave K_{sp}^2 is not larger than about 0.1%.

Please cancel claim 2 without prejudice or disclaimer of the subject matter contained therein.

Please add the following new claim 14:

14. A surface acoustic wave device, comprising:

a quartz substrate;

a piezoelectric thin film disposed on said quartz substrate;

comb electrodes disposed between said quartz substrate and said piezoelectric thin film; and

the normalized film thickness H/λ of said piezoelectric thin film is at least about 0.20, wherein the film thickness of said piezoelectric thin film is H, and the wavelength of a surface acoustic wave is λ; wherein

the Euler angles of said quartz substrate are within a range such that the power flow angle PFA of a Rayleigh wave is within about $\pm$ 2.5°;

said range of the Euler angles set such that the PFA is within about ± 2.5° is within an area surrounded by lines which are represented by the following equations:

θ=201.77292-8.1909*ψ+0.3257*ψ^2-0.00532*ψ^3+0.0000286691*ψ^4 and 3≦ψ≦40;

θ=-2.3333*ψ+221.33 and 40≦ψ≦43;

θ=-20.667*ψ+1009.7 and 43≦ψ≦44.5;

ψ=242.92932-2.46296*θ-0.04285*θ^2+0.000792121*θ^3-0.00000316309*θ^4 and 60≦ψ≦106;

θ=60 and 28≦ψ≦70;

θ=1.39744*ψ^2-78.37179*ψ+1158.8 and 27.5≦ψ≦32;

θ=9.8429+15.55204*ψ-1.0153*ψ^2+0.0306*ψ^3-0.00038175*ψ^4 and 3≦ψ≦32;

θ=60 and 0≦ψ≦4;

ψ=0 and 60≦θ≦180;

θ=180 and 0≦ψ≦4; and

the Euler angles of said quartz substrate are within a range such that the electromechanical coupling coefficient for a spurious wave, K_{sp}^2 is not larger than about 0.05%;

said range of the Euler angles set such that K_{sp}^2 is not larger than about 0.05% is within an area surrounded by lines which are represented by the following equations:

θ=461.5-51.23992*ψ+3.55894*ψ^2-0.12153*ψ^3+0.00171*ψ^4 and 12≦ψ≦25.5;

θ=-10*ψ+425 and 24≦ψ≦25.5;

θ=-88.97104+38.79904*ψ-1.80561*ψ^2+0.03334*ψ^3-0.000217323*ψ^4 and 27≦ψ≦43;

θ=-0.013928594*ψ^4+2.255507173*ψ^3-136.803833233*ψ^2+3684.063042727*ψ-37024.00 and 33≦ψ≦43;

θ=0.0009461088154*ψ^4-0.178399621211*ψ^3+12.5950972795403*ψ^2-395.999782194768*ψ+4763.57 and 33≦ψ≦55;

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$\theta=60$ and $29 \leqq \psi \leqq 55$;

$\theta=0.01724063*\psi^3-1.20723413*\psi^2+24.63357158*\psi-58$ and $16 \leqq \psi \leqq 30$;

$\theta=0.0139*\psi^2+0.9028*\psi+79$ and $79 \leqq \psi \leqq 100$;

$\psi=0$ and $78 \leqq \theta \leqq 180$;

$\theta=180$ and $0 \leqq \psi \leqq 13$;

$\theta=180$ and $24 \leqq \psi \leqq 29$.